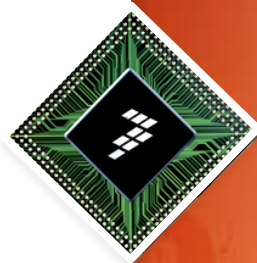




The R3 Model: Homework Solutions

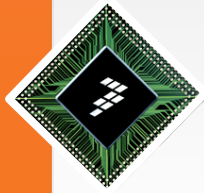
Colin McAndrew

Tempe
USA



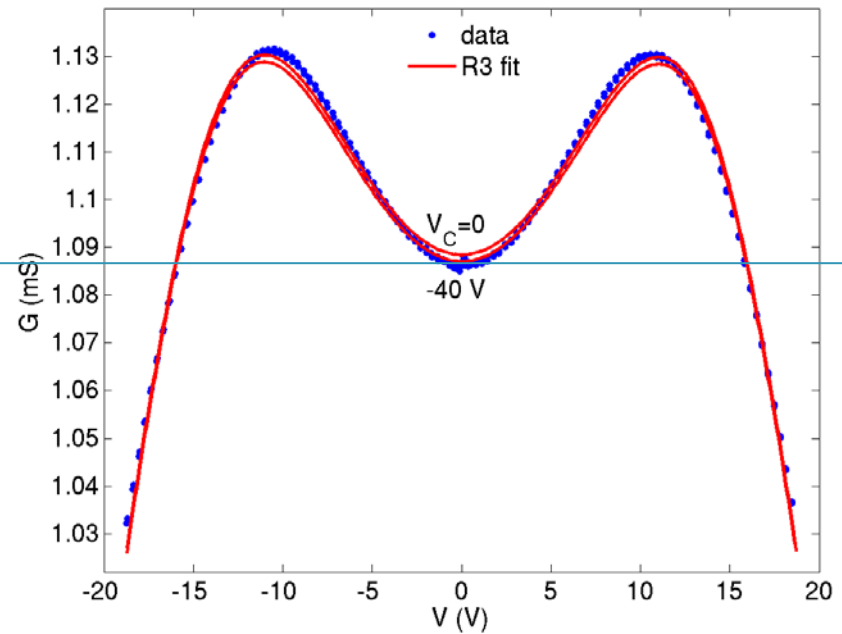
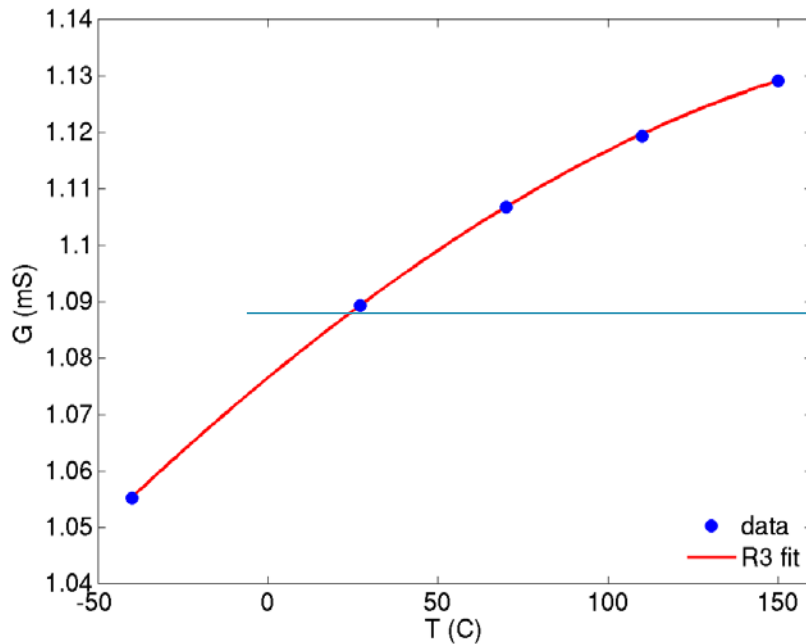
NEEDS Workshop
November 18-19, 2014

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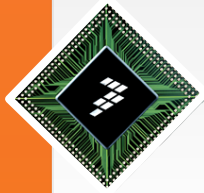


Homework (8)

- From plots below, what is approx. max. resistor temperature?
- hint: there's a reason the $G(T)$ plot is on the left

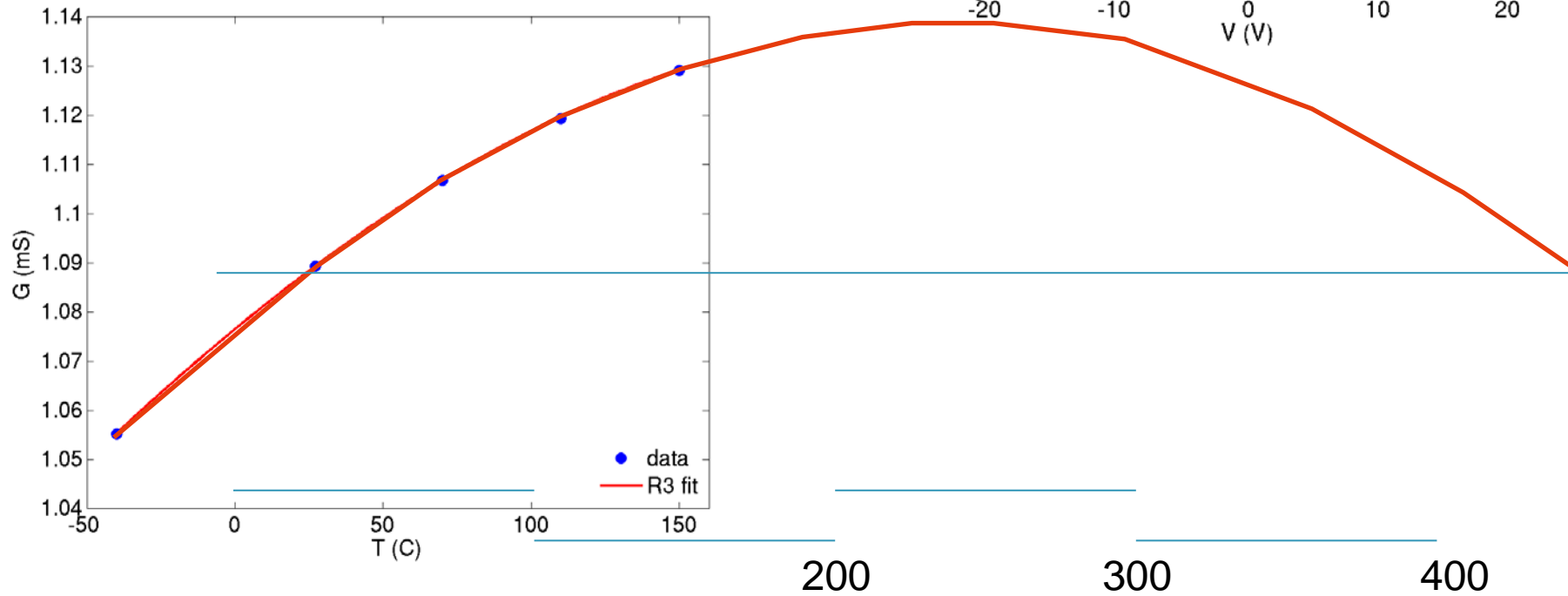


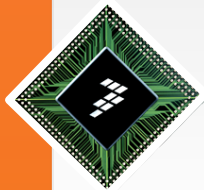
$$G_0 = \lim_{V \rightarrow 0} G(V, V_c = 0)$$



Solution (8)

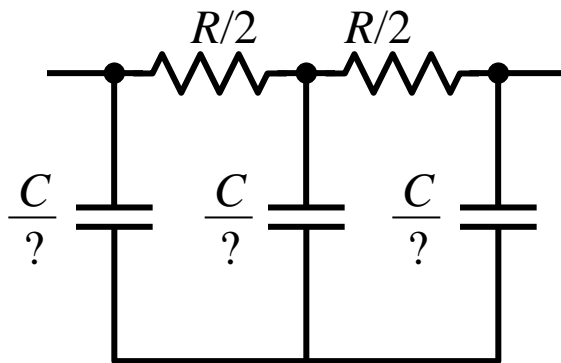
- Extrapolate $G(T)$ to where it reduces below $G(27)$

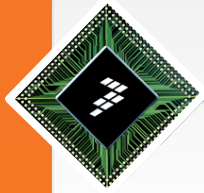




Homework (7)

- Consider a resistor split into two sections, to increase the frequency range over which modeling is accurate. How should the capacitance be split?
 - 1/3, 1/3, 1/3
 - 1/4, 1/2, 1/4
 - or is there a more accurate way?
 - hint: compare the input admittance of a distributed RC model to the two-R lumped section model (with port 2 shorted to ground)

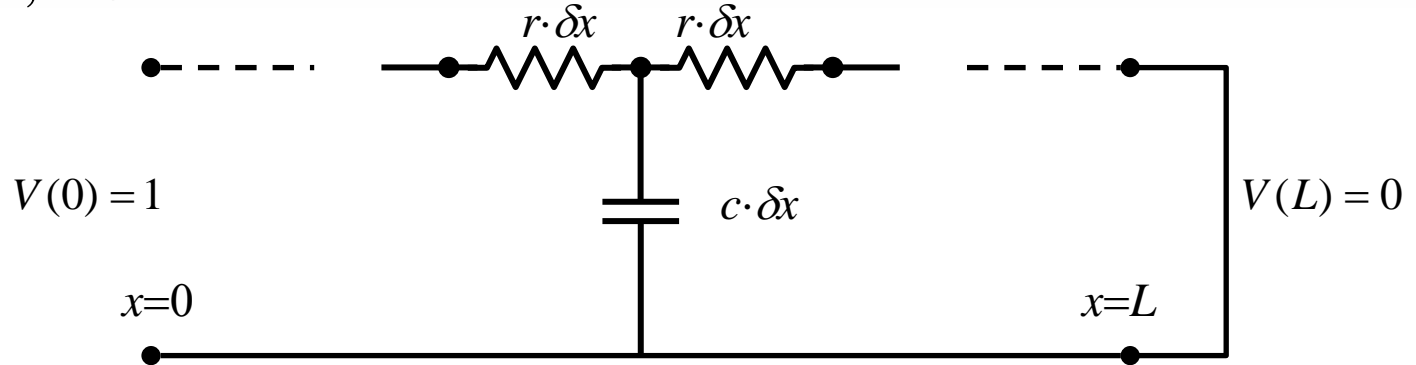




Solution (7) Distributed RC Analysis

$$R = r \cdot L, \quad C = c \cdot L$$

$$I(x) = -\frac{1}{r} \cdot \frac{\partial V}{\partial x}$$

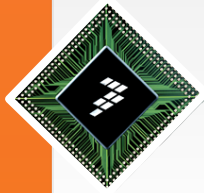


$$c \cdot \delta x \cdot \frac{\partial V(x)}{\partial t} = \frac{V(x - \delta x) - V(x)}{r \cdot \delta x} + \frac{V(x + \delta x) - V(x)}{r \cdot \delta x} = \frac{V(x - \delta x) - 2V(x) + V(x + \delta x)}{r \cdot \delta x}$$

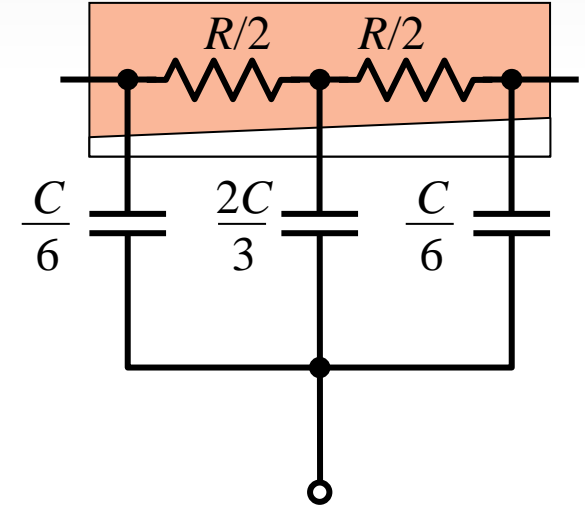
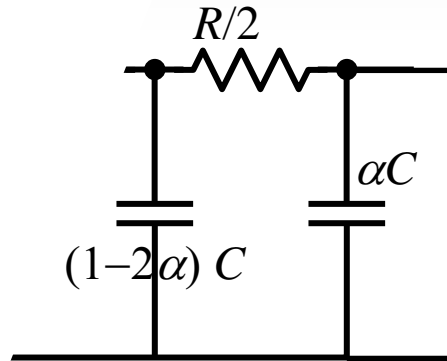
$$\frac{\partial^2 V}{\partial x^2} = rc \cdot \frac{\partial V}{\partial t} = \frac{\gamma^2}{L^2} \cdot V, \quad \gamma = \sqrt{j\omega RC}$$

$$V = \cosh\left(\gamma \frac{x}{L}\right) - \operatorname{ctnh}(\gamma) \sinh\left(\gamma \frac{x}{L}\right)$$

$$Y_{in} = I(0) = \frac{\gamma \operatorname{ctnh}(\gamma)}{R} \approx \frac{1}{R} \left(1 + \frac{\gamma^2}{3}\right)$$



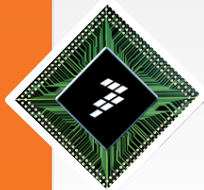
Solution (7)



$$y_1 = \frac{2}{R} + j\omega(1-2\alpha)C = \frac{2}{R} \left(1 + j\omega \frac{(1-2\alpha)}{2} RC \right)$$

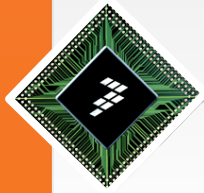
$$z_2 = \frac{R}{2} + \frac{R}{2} \frac{1}{1 + j\omega \frac{(1-2\alpha)}{2} RC} \approx R \left(1 - j\omega \frac{(1-2\alpha)}{4} RC \right)$$

$$Y_{in} \approx j\omega\alpha C + \frac{1}{R} \left(1 + j\omega \frac{(1-2\alpha)}{4} RC \right) = \frac{1}{R} \left(1 + j\omega \frac{(1+2\alpha)}{4} RC \right) \Rightarrow \frac{1+2\alpha}{4} = \frac{1}{3}, \quad \alpha = \frac{1}{6}$$

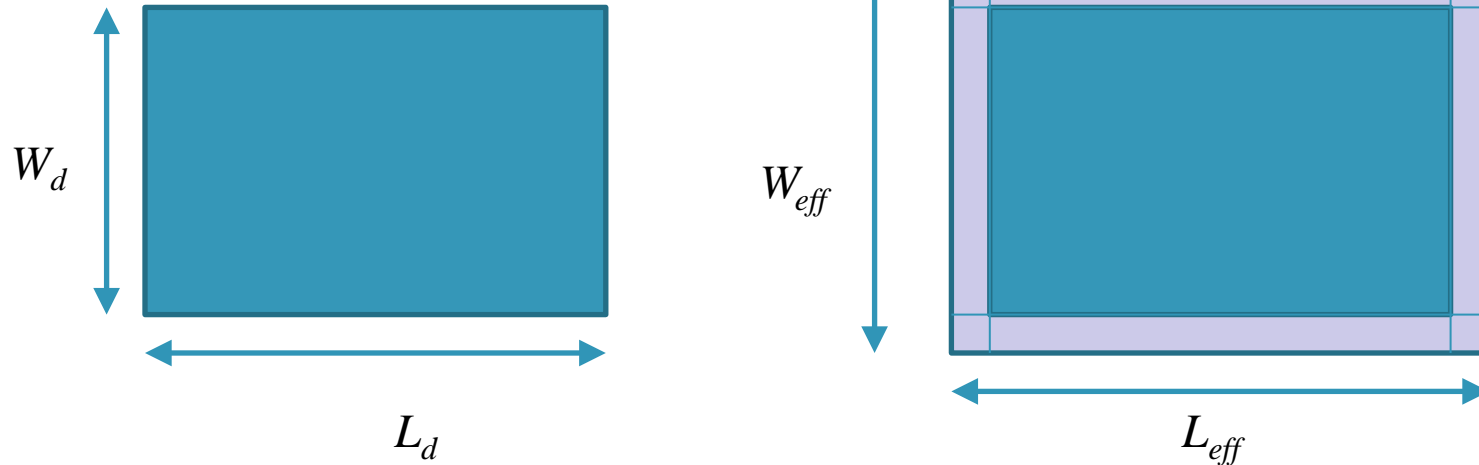


Homework (6)

- Show that for quantities that scale geometrically with fixed (corner), perimeter, and area components there is no need to consider effective, as compared to drawn dimensions; i.e. that the difference between these can be handled by appropriate modification of the coefficients.

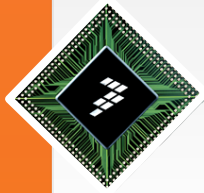


Solution (6)



$$\begin{aligned}
 C &= 4C'_c + 2(L_{eff} + W_{eff}) \cdot C'_p + (L_{eff} \cdot W_{eff}) \cdot C'_a \\
 &= 4C'_c + 2(L_d + W_d + 4\delta) \cdot C'_p + (L_d + 2\delta) \cdot (W_d + 2\delta) \cdot C'_a \\
 &= 4(C'_c + 2\delta \cdot C'_p + \delta^2 \cdot C'_a) + 2(L_d + W_d) \cdot (C'_p + \delta \cdot C'_a) + (L_d \cdot W_d) \cdot C'_a
 \end{aligned}$$

Difference between drawn and effective dimensions simply accounted for by modification of perimeter and corner capacitance component coefficients

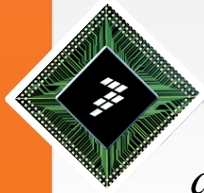


Homework (5)

- The solution for V_{sat} becomes numerically unstable when the amount of depletion pinching (i.e. d_f) becomes small, as happens in poly resistors. Look in the `r3` code and see how that situation is handled.
 - why is the error this introduces of no practical consequence?

$$V_{sat} \text{ is solution of } \frac{\partial}{\partial V} \left(V \frac{1 - d_f \sqrt{d_{pe} + V}}{\frac{V}{L} - E_{co}} \right) = 0 \quad \text{where} \quad d_{pe} = d_p - 2V_{c1}, \quad L_{DE} = L(E_{cr} - E_{co})$$

$$\frac{d_f^2}{4L_{DE}^2} V_{sat}^4 + \frac{3d_f^2}{2L_{DE}} V_{sat}^3 + d_f^2 \left(\frac{9}{4} + \frac{p_e}{L_{DE}} \right) V_{sat}^2 + (3d_f^2 p_e - 1) V_{sat} + p_e (d_f^2 p_e - 1) = 0$$



Solution (5)

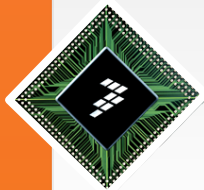
$$\frac{d_f^2}{4L_{DE}^2}V_{sat}^4 + \frac{3d_f^2}{2L_{DE}}V_{sat}^3 + d_f^2\left(\frac{9}{4} + \frac{p_e}{L_{DE}}\right)V_{sat}^2 + (3d_f^2 p_e - 1)V_{sat} + p_e(d_f^2 p_e - 1) = 0$$

```

if (iecrit>0.0) begin \
    a0      =  dfsq*dpe*dpe-dpe; \
    a1      = -1.0+3.0*dfsq*dpe; \
    a2      =  dfsq*(9.0/4.0+dpe/lde); \
    a3      =  1.5*dfsq/lde; \
    a4      =  4.0*lde*lde/dfsq; \
dfmin      =  sqrt(dp)/(dp+1.0e4); // min value of df for stable Vsat calculation
df         =  (sw_lin) ? 0.0 : dfinf+(dfw*len+df1*width+dfwl)/(len*width);
if (df<dfmin) begin // for highly linear (e.g. poly) resistors limit
    df      =  `MAX(df,0.0); // dfsq, which is only used for Vsat calculation
    dfsq    =  dfmin*dfmin; // this underestimates Vsat, but that is not of
end else begin // consequence as it is very large anyway
    dfsq    =  df*df;
end
end

```

- “Fudged” (very small, but finite) `dfsq` is used
 - V_{sat} is **so** big it is well beyond any reasonable range of V
 - has no discernable affect
 - very small `df` means device never gets near pinch-off



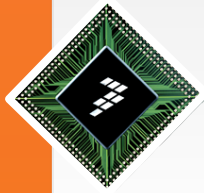
Homework (4)

- In $\text{r}3$, V_{sat} is calculated as the value of V at which

$$g_o = \frac{\partial I_{depl}}{\partial V \mu_{red}} = 0$$

but using an asymptotic model for μ_{red} that is **less** than the actual μ_{red} model used to calculate I . This would seem to imply that when used with the actual μ_{red} model, which degrades the mobility **more**, g_o (in the absence of self-heating) at V_{sat} would be negative. However, this is not the case, it is guaranteed that $g_o(V_{sat})$ is positive. Prove this.

- hint: write down an expression for g_o and see how this changes when the μ_{red} model, but not V_{sat} , is changed
- do you think the μ_{red} form used in $\text{r}3$ makes the velocity-field relationship monotonic or non-monotonic? (Note: it is non-trivial to *prove* which it is, you do not need to generate a proof)

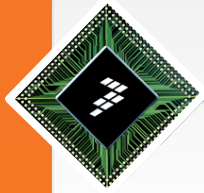


Solution (4)

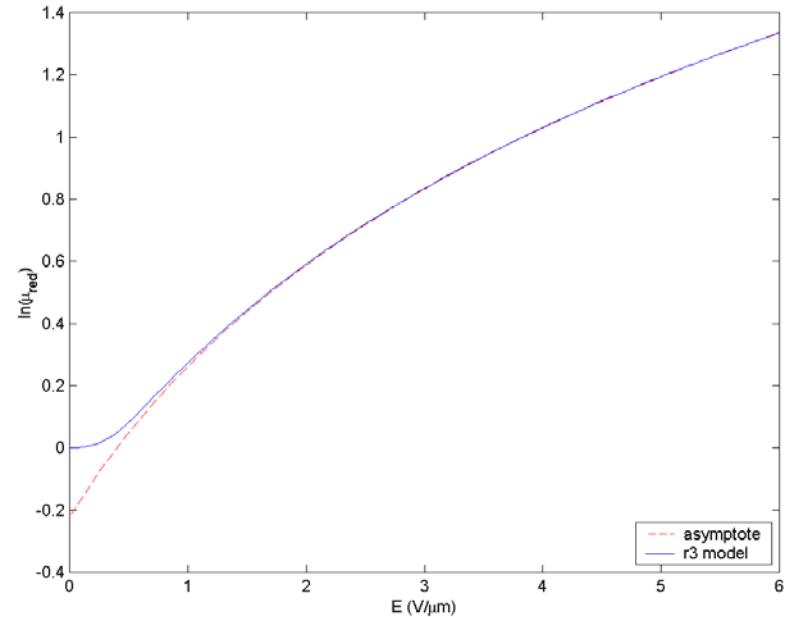
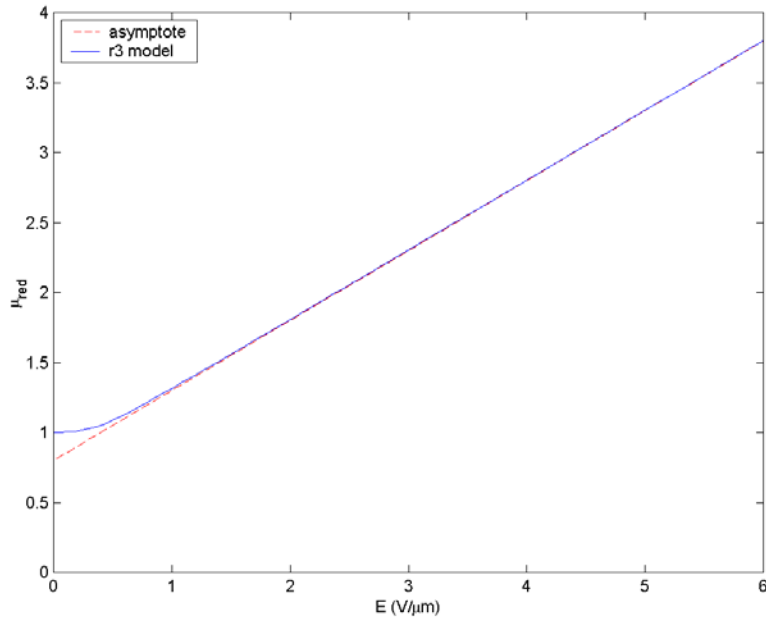
- Let I_{depl} be the current without velocity saturation, add a superscript prime for asymptotic mobility reduction model

$$V_{sat} = V \mid \frac{\partial}{\partial V} \frac{I_{depl}}{\mu'_{red}} = \frac{g_{depl} - I_{depl} \frac{d \ln(\mu'_{red})}{dV}}{\mu'_{red}} = 0, \quad g_{depl} = \frac{\partial I_{depl}}{\partial V}$$

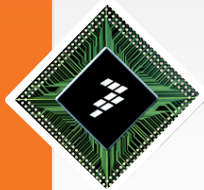
- If $\frac{d \ln(\mu_{red})}{dV} \leq \frac{d \ln(\mu'_{red})}{dV}$ then $g_o(V_{sat}) \geq 0$ as desired



Solution (4)



- Velocity-field relationship **is** monotonic provided $E_{co} < E_{cr}$

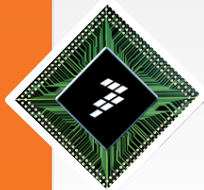


Homework (3)

- When `sw_lin=1`, is `r3` **exactly** linear?
 - hint: look at how `sw_lin` affects `DP`, `VS`, and `SH`
 - what else could possibly induce a non-linearity
- Run the script `simulateLinear.pl`

```
if (iecrit>0.0) begin \  
    fctrm    = 0.5*((Vbeff/leffE_um)-ecrneff)*iecrit; \  
    fctrp    = 0.5*((Vbeff/leffE_um)+ecrneff)*iecrit; \  
    sqrtm    = sqrt(fctrm*fctrm+dufctr); \  
    sqrtp    = sqrt(fctrp*fctrp+dufctr); \  
    rmu      = sqrtm+sqrtp-uoff; \  
end else begin \  
    rmu      = 0.0; \  
end \  
dpfctr     = 1.0-df*sqrt(dpe+Vbeff); \  
geff       = gf*dpfctr/(1.0+rmu); \  
Ib         = sdFlip*geff*Vbeff; \  

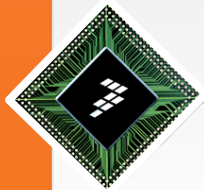
```



Solution (3)

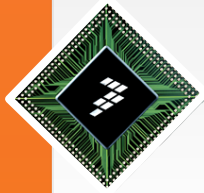
- Left out one important line (top line below)
 - makes $V_{beff}(V_b)$ nonlinear
 - even though limiting is $\text{sqrt}()$ rather than $\text{log}(\text{exp}())$, V_{sat} is still so big it introduces negligible nonlinearity

```
Vbeff      = 2.0*Vbi*Vsat/ \
  (sqrt((Vbi-Vsat)*(Vbi-Vsat)+atspo)+sqrt((Vbi+Vsat)*(Vbi+Vsat)+atspo)); \
if (iecrit>0.0) begin \
  fctrm    = 0.5*((Vbeff/leffE_um)-ecrneff)*iecrit; \
  fctrp    = 0.5*((Vbeff/leffE_um)+ecrneff)*iecrit; \
  sqrtm    = sqrt(fctrm*fctrm+dufctr); \
  sqrtp    = sqrt(fctrp*fctrp+dufctr); \
  rmu      = sqrtm+sqrtp-uoff; \
end else begin \
  rmu      = 0.0; \
end \
dpfctr    = 1.0-df*sqrt(dpe+Vbeff); \
geff      = gf*dpfctr/(1.0+rmu); \
Ib        = sdFlip*geff*Vbeff; \
```



Homework (2)

- Look over and run the “simulatePoly.pl” script, which
 - reads data from a $L/W=42\mu\text{m}/4.2\mu\text{m}$ poly resistor
 - sets up parameters extracted from that resistor
 - not exactly the same parameters used in the TSM paper
 - runs r3 simulations
 - not exactly for the same biases
 - plots the measured data and simulation results
- Modify these parameters (one at a time), see what happens
 - rsh, dfinf, tc1, tc2, gtha
- Explain qualitatively why the curves change the way they do



Solution (2)

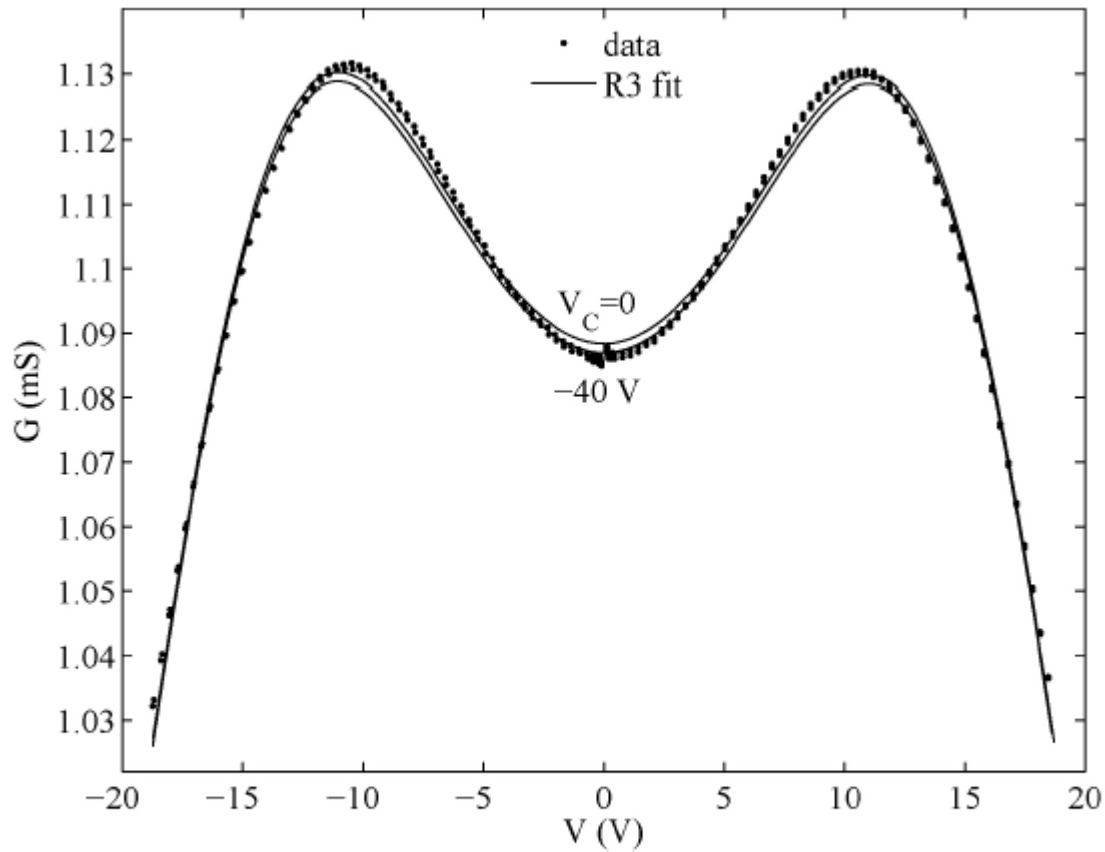
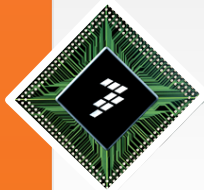


Fig. 13. R3 $G(V)$ for an $87 \Omega/\square$ poly resistor, $L/W = 42 \mu\text{m}/4.2 \mu\text{m}$. Inset shows temperature rise.



Homework (1)

- Go through the code of the core r3 macro
 - do **not** worry about the pinch-off and limiting code
 - ignore “vpo” and “swaccpo” code, they are complex
- Identify
 - where the flipping of terminals 1 and 2 is done
 - where DIBL is included as a shift in the effective control voltage
 - where the saturation voltage is calculated
 - where the limiting to V_{sat} is done
 - where the depletion factor and r_{μ} are calculated
 - where CLM is applied
- Where is self-heating handled?